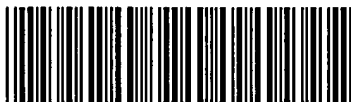


Search Notes

Application/Control No.

10/676,961

Examiner

Chris C. Chu

Applicant(s)/Patent under
Reexamination

PON ET AL.

Art Unit

2815

SEARCHED

Class	Subclass	Date	Examiner
257	723, 686, 685, 646, 693 & 777	12/27/2004	C.C.
257	784 & 786	12/27/2004	C.C.
257	676	12/27/2004	C.C.
361	760	12/27/2004	C.C.
438	108 & 109	12/27/2004	C.C.
438	612	12/27/2004	C.C.

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Searched in US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; and IBM_TDB;	12/27/2004	C.C.